

SLOVENSKI STANDARD SIST EN IEC 60793-1-45:2024

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Optična vlakna - 1-45. del: Merilne metode in postopki preskušanja - Premer osnovnega rodu

Optical fibres - Part 1-45: Measurement methods and test procedures - Mode field diameter

Lichtwellenleiter - Teil 1-45: Messmethoden und Prüfverfahren - Modenfelddurchmesser

Fibres optiques - Partie 1-45 : Méthodes de mesure et procédures d'essai - Diamètre du champ de mode

Ta slovenski standard je istoveten z: EN IEC 60793-1-45:2024

ICS:

33.180.10 (Optična) vlakna in kabli Fibres and cables

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EUROPEAN STANDARD NORME EUROPÉENNE FUROPÄISCHE NORM

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English Version

Optical fibres - Part 1-45: Measurement methods and test procedures - Mode field diameter (IEC 60793-1-45:2024)

Fibres optiques - Partie 1-45 : Méthodes de mesure et procédures d'essai - Diamètre du champ de mode (IEC 60793-1-45:2024)

Lichtwellenleiter - Teil 1-45: Messmethoden und Prüfverfahren - Modenfelddurchmesser (IEC 60793-1-45:2024)

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CEN-CENELEC Management Centre: Rue de la Science 23, B-1040 Brussels

EN IEC 60793-1-45:2024 (E)

European foreword

The text of document 86A/2300/CDV, future edition 3 of IEC 60793-1-45, prepared by SC 86A "Fibres and cables" of IEC/TC 86 "Fibre optics" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN IEC 60793-1-45:2024.

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In the official version, for Bibliography, the following note has to be added for the standard indicated:

IEC 60793-2

NOTE

Approved as EN IEC 60793-2

EN IEC 60793-1-45:2024 (E)

Annex ZA (normative)

Normative references to international publications with their corresponding European publications

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 Where an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cencenelec.eu.

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IEC 60793-1-45

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INTERNATIONAL STANDARD

NORME INTERNATIONALE

Optical fibres -

Part 1-45: Measurement methods and test procedures - Mode field diameter

Fibres optiques - https://standards.iteh_ai

Partie 1-45 : Méthodes de mesure et procédures d'essai – Diamètre du champ de mode

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

OPTICAL FIBRES -

Part 1-45: Measurement methods and test procedures – Mode field diameter

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IEC 60793-1-45 has been prepared by subcommittee 86A: Fibres and cables, of IEC technical committee 86: Fibre optics. It is an International Standard.

This third edition cancels and replaces the second edition published in 2017. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- a) Modification of the minimum distance between the fibre end and the detector for the direct far field scan (Annex A).
- b) Generalization of the requirement for the minimum dynamic range for all fibre types (Annex A).